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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

DOCKET: F1S920030145US1

PATENT

INVENTOR: John Bruley et al.

) EXAMINER: Phuc T. Dang

SERIAL NO.: 10/605,258

) ART UNIT: 2818

FILING DATE: September 18, 2003

) DATE: December 8, 2004

FOR: SITE-SPECIFIC
METHODOLOGY FOR
LOCALIZATION AND
ANALYZING JUNCTION
DEFECTS IN MOSFET DEVICES

)

AMENDMENT UNDER RULE 312

Mail Stop ISSUE FEE
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Responsive to the Notice of Allowance mailed November 15, 2004, please
amend the above-identified application as follows: